


<b>Search Notes</b>  	<b>Application/Control No.</b>  10816451	<b>Applicant(s)/Patent Under Reexamination</b>  CHUN ET AL.
	<b>Examiner</b>  BENJAMIN P GEIB	<b>Art Unit</b>  2181

SEARCHED			
Class	Subclass	Date	Examiner
718	102	6/3/2009	BPG
712	201,245	6/3/2009	BPG

SEARCH NOTES		
Search Notes	Date	Examiner
Updated EAST search	6/3/2009	BPG
Updated NPL search (Google Scholar, IEEE Xplore, Citeseer)	6/3/2009	BPG
Inventor name search	6/3/2009	BPG

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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